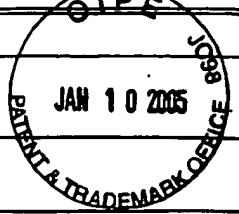

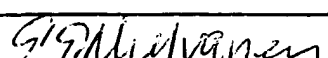
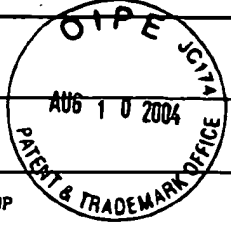


Sheet 1 of 1		INFORMATION DISCLOSURE STATEMENT						
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: January 10, 2005		ATTY DOCKET NO. 2004_0297A		SERIAL NO. 10/787,301		<div style="text-align: center;">  </div>		
		APPLICANT Takashi NISHIHARA et al.						
		FILING DATE February 27, 2004			GROUP 2655			
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
	AJ	10-275360	10-13-98	Japan			abstract	
	AK							
	AL							
	AM							
	AN							
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AO							
	AP							
	AQ							
EXAMINER 				DATE CONSIDERED 3-15-05				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include cop. this form with next communication to applicant.

Sheet 1 of 1		FORM PTO 1449 (modified)		ATTY DOCKET NO. 2004_0297A		SERIAL NO. 10/787,301			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Takashi NISHIHARA et al.					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE February 27, 2004					
Date Submitted to PTO: August 10, 2004				GROUP 2655					
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
	AA								
FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO		
↓	AB	1 172 811	1-16-02	Europe			X		
	AC	1 187 119	3-13-02	Europe			X		
	AD	0 217 293	4-8-87	Europe			X		
	AE	8-321041	12-3-96	Japan			abstract		
	AF	0 184 452	6-11-86	Europe			X		
	AG	2004/025640	3-25-04	WO			abstract		
	AH	1 324 326	7-2-03	Europe			X		
↓	AI	1 351 229	10-8-03	Europe			X		
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)									
↓	AJ	M. Horie et al., "Material Characterization and Application of Eutectic SbTe Based Phase-Change Optical Recording Media" Proceedings of the SPIE, SPIE, Bellingham, VA, US, vol. 4342, April 2001 (04-2001), pages 76-87							
	AK	T. AKIYAMA et al., "Rewritable Dual-Layer Phase-Change Optical Disk Utilizing a Blue-Violet Laser", Japanese Journal of Applied Physics, Publication Office Japanese Journal of Applied Physics, Tokyo, JP, vol. 40, no. 3B, 2001, pages 1598-1603							
	AL	R. KOJIMA et al., "Acceleration of Crystallization Speed by Sn Addition to Ge-Sb-Te Phase-Change Recording Material" JPN, J. Appl. Phys. 1, Regul. Pap. Short Notes Rev. Pap. (Japan), Japanese Journal of Applied Physics, Part 1 (Regular Papers, Short Notes & Review Papers), Oct. 2001, Japan Soc. Appl. Phys., Japan, vol. 40, no. 10, October 2001 (10-2001), pages 5930-5937							
	AM	K. NARUMI et al., "Rewritable Dual-Layer Phase-Change Optical Disk with a Balanced Transmittance Structure" Japanese Journal of Applied Physics, Publication Office Japanese Journal of Applied Physics, Tokyo, JP, vol. 41, no. 5A, Part 1, May 2002 (05-2002), pages 2925-2930							
↓	AN	K. YUSU et al., "Advanced Phase Change Medium of over 30GB Capacity for Blue Laser and High-NA Objective Lens", Joint International Symposium on Optical Memory and Optical Data Storage 2002, Technical Digest, Waikoloa, HI, USA, July 7-11 2002, July 7, 2002 (07-07-2002), pages 413-415							
EXAMINER				DATE CONSIDERED					
G. J. Mulvaney				3-15-05					

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Sheet 1 of 1							
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: February 27, 2004				ATTY DOCKET NO. 2004_0297A		SERIAL NO. NEW	
APPLICANT Takashi NISHIHARA et al.				FILING DATE February 27, 2004		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
gjm	AJ	2002-144736	5-22-02	Japan			abstract
gjm	AK	2000-36130	2-2-00	Japan			abstract
	AL						
	AM						
	AN						
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AO						
	AP						
	AQ						
EXAMINER				DATE CONSIDERED			
gjm				3-15-05			

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